



MAIN FEATURES

- ▶ Burn-in & Test System for a wide range of devices
- ▶ Suitable for FLASH devices
- ▶ Flexible dynamic H/W and F/W configuration
- ▶ Modular architecture based on PTDM (Pattern Test Driver Module)
- ▶ Unique PTDM module for each BIB
- ▶ PTDM includes pattern generator, DUT voltages and driver-testing
- ▶ Ethernet network architecture for each PTDM
- ▶ User-friendly Software Interface
- ▶ Up to 108A for each BIB
- ▶ Test Pattern Conversion Software for digital application

